

Data Sheet

October 2004

72A, 1200V, NPT Series N-Channel IGBT

The HGTG27N120BN and HGT5A27N120BN are **N**on-**P**unch Through (NPT) IGBT design. This is a new member of the MOS gated high voltage switching IGBT family. IGBTs combine the best features of MOSFETs and bipolar transistors. This device has the high input impedance of a MOSFET and the low on-state conduction loss of a bipolar transistor.

The IGBT is ideal for many high voltage switching applications operating at moderate frequencies where low conduction losses are essential, such as: AC and DC motor controls, power supplies and drivers for solenoids, relays and contactors.

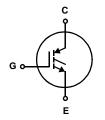
Formerly Developmental Type TA49280.

Ordering Information

PART NUMBER	PACKAGE	BRAND
HGTG27N120BN	TO-247	G27N120BN
HGT5A27N120BN	TO-247-ST	27N120BN

NOTE: When ordering, use the entire part number.

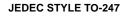
Symbol

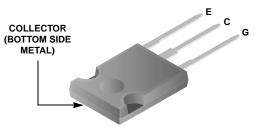


Features

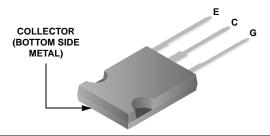
- 72A, 1200V, T_C = 25^oC
- 1200V Switching SOA Capability
- Typical Fall Time..... 140ns at T_J = 150^oC
- Short Circuit Rating
- Low Conduction Loss
- Thermal Impedance SPICE Model
 Temperature Compensating SABER™ Model
 www.fairchildsemi.com
- Avalanche Rated

Packaging





JEDEC STYLE TO-247-ST



FAIRCHILD SEMICONDUCTOR IGBT PRODUCT IS COVERED BY ONE OR MORE OF THE FOLLOWING U.S. PATENTS

4,364,073	4,417,385	4,430,792	4,443,931	4,466,176	4,516,143	4,532,534	4,587,713
4,598,461	4,605,948	4,620,211	4,631,564	4,639,754	4,639,762	4,641,162	4,644,637
4,682,195	4,684,413	4,694,313	4,717,679	4,743,952	4,783,690	4,794,432	4,801,986
4,803,533	4,809,045	4,809,047	4,810,665	4,823,176	4,837,606	4,860,080	4,883,767
4,888,627	4,890,143	4,901,127	4,904,609	4,933,740	4,963,951	4,969,027	

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	HGTG27N120BN	UNITS
Collector to Emitter VoltageBV _{CES}	1200	V
Collector Current Continuous		
At $T_{C} = 25^{\circ}C$ I_{C25}	72	А
At $T_{C} = 110^{\circ}C$ I_{C110}	34	А
Collector Current Pulsed (Note 1) I _{CM}	216	А
Gate to Emitter Voltage ContinuousV _{GES}	±20	V
Gate to Emitter Voltage PulsedV _{GEM}	±30	V
Switching Safe Operating Area at T _J = 150 ^o C (Figure 2) SSOA	150A at 1200V	
Power Dissipation Total at $T_C = 25^{\circ}C$ P_D	500	W
Power Dissipation Derating T _C > 25 ^o C	4.0	W/ ^o C
Forward Voltage Avalanche Energy (Note 2)	135	mJ
Operating and Storage Junction Temperature Range	-55 to 150	°C
Maximum Lead Temperature for Soldering TL	260	°C
Short Circuit Withstand Time (Note 3) at V _{GE} = 15Vt _{SC}	8	μs
Short Circuit Withstand Time (Note 3) at V _{GE} = 12Vt _{SC}	15	μs

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

- 1. Pulse width limited by Max junction temperature.
- 2. $I_{CE} = 30A$, $L = 400\mu H$, $T_J = 125^{o}C$
- 3. $V_{CE(PK)} = 960V$, $T_J = 125^{\circ}C$, $R_G = 3\Omega$

Electrical Specifications $T_{C} = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Collector to Emitter Breakdown Voltage	BVCES	$I_{C} = 250 \mu A, V_{GE} = 0 V$		1200	-	-	V
Emitter to Collector Breakdown Voltage	BVECS	I _C = 10mA, V _{GE} =	= 0V	15	-	-	V
Collector to Emitter Leakage Current	ICES	V _{CE} = 1200V	$T_C = 25^{\circ}C$	-	-	250	μΑ
			T _C = 125 ^o C	-	300	-	μA
			T _C = 150 ^o C	-	-	4	mA
Collector to Emitter Saturation Voltage	V _{CE(SAT)}	I _C = 27A,	$T_C = 25^{\circ}C$	-	2.45	2.7	V
		$V_{GE} = 15V$	T _C = 150 ^o C	-	3.8	4.2	V
Gate to Emitter Threshold Voltage	V _{GE(TH)}	$I_{C} = 250 \mu A, V_{CE}$	= V _{GE}	6	6.6	-	V
Gate to Emitter Leakage Current	IGES	$V_{GE} = \pm 20V$		-	-	±250	nA
Switching SOA	SSOA	$T_J = 150^{\circ}C, R_G = 3\Omega, V_{GE} = 15V,$ L = 200µH, V _{CE(PK)} = 1200V		150	-	-	A
Gate to Emitter Plateau Voltage	V _{GEP}	$I_{C} = I_{C110}, V_{CE} = 0.5 \text{ BV}_{CES}$		-	9.2	-	V
On-State Gate Charge	Q _{G(ON)}	$\begin{array}{c} Q_{G(ON)} & I_{C} = 27A, \\ V_{CE} = 600V & & \\ \end{array} \\ \begin{array}{c} V_{GE} = 15V \\ V_{GE} = 20V \end{array}$		-	270	325	nC
				-	350	420	nC
Current Turn-On Delay Time	^t d(ON)I	$\label{eq:GBT} \begin{array}{l} \text{IGBT and Diode at } T_{J} = 25^{\text{O}}\text{C}, \\ I_{\text{CE}} = 27\text{A}, \\ V_{\text{CE}} = 960\text{V}, \\ V_{\text{GE}} = 15\text{V}, \\ R_{\text{G}} = 3\Omega, \end{array}$		-	24	30	ns
Current Rise Time	t _{rl}			-	20	25	ns
Current Turn-Off Delay Time	t _{d(OFF)} I			-	195	240	ns
Current Fall Time	t _{fl}			-	80	120	ns
Turn-On Energy (Note 5)	E _{ON1}	L = 1mH, Test Circuit (Figu	-	2.2	-	mJ	
Turn-On Energy (Note 5)	E _{ON2}		-	2.7	3.3	mJ	
Turn-Off Energy (Note 4)	E _{OFF}		-	2.3	2.8	mJ	

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Current Turn-On Delay Time	^t d(ON)I	IGBT and Diode at $T_J = 150^{\circ}C$,	-	22	28	ns
Current Rise Time	t _{rl}	□ I _{CE} = 27A, V _{CE} = 960V,	-	20	25	ns
Current Turn-Off Delay Time	^t d(OFF)I	$V_{GE} = 900V$, $V_{GE} = 15V$,	-	220	280	ns
Current Fall Time	t _{fl}	$R_{G} = 3\Omega,$	-	140	200	ns
Turn-On Energy (Note 5)	E _{ON1}	L = 1mH, Test Circuit (Figure 18)	-	2.7	-	mJ
Turn-On Energy (Note 5)	E _{ON2}		-	5.1	6.5	mJ
Turn-Off Energy (Note 4)	E _{OFF}		-	3.4	4.2	mJ
Thermal Resistance Junction To Case	R _{θJC}		-	-	0.25	°C/W

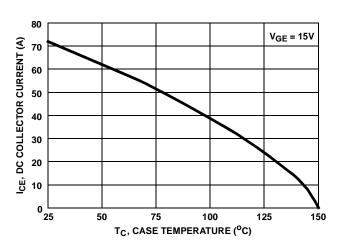
Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified (Continued)

NOTES:

4. Turn-Off Energy Loss (E_{OFF}) is defined as the integral of the instantaneous power loss starting at the trailing edge of the input pulse and ending at the point where the collector current equals zero (I_{CE} = 0A). All devices were tested per JEDEC Standard No. 24-1 Method for Measurement of Power Device Turn-Off Switching Loss. This test method produces the true total Turn-Off Energy Loss.

5. Values for two Turn-On loss conditions are shown for the convenience of the circuit designer. E_{ON1} is the turn-on loss of the IGBT only. E_{ON2} is the turn-on loss when a typical diode is used in the test circuit and the diode is at the same T_J as the IGBT. The diode type is specified in Figure 18.

Typical Performance Curves Unless Otherwise Specified





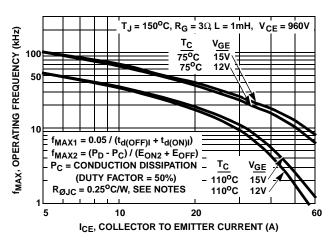


FIGURE 3. OPERATING FREQUENCY vs COLLECTOR TO EMITTER CURRENT

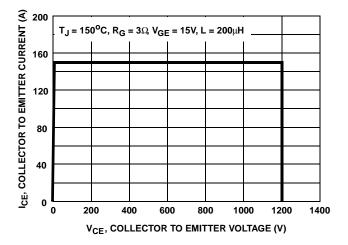


FIGURE 2. MINIMUM SWITCHING SAFE OPERATING AREA

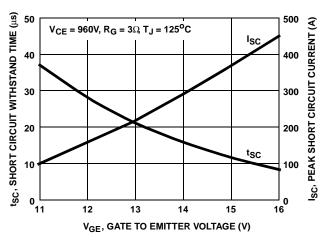


FIGURE 4. SHORT CIRCUIT WITHSTAND TIME

Typical Performance Curves Unless Otherwise Specified (Continued)

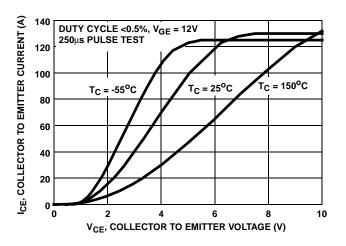
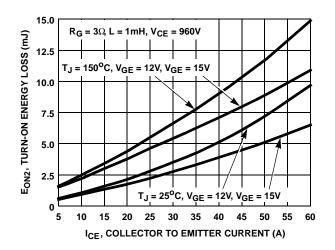
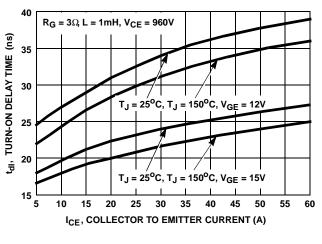


FIGURE 5. COLLECTOR TO EMITTER ON-STATE VOLTAGE









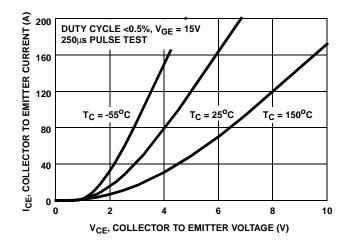
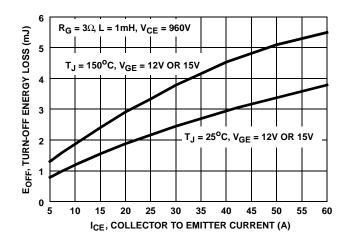
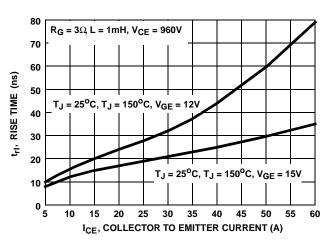


FIGURE 6. COLLECTOR TO EMITTER ON-STATE VOLTAGE

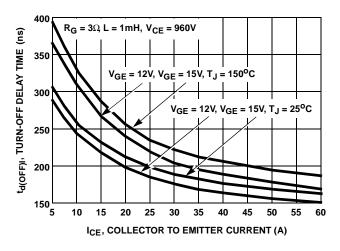








Typical Performance Curves Unless Otherwise Specified (Continued)





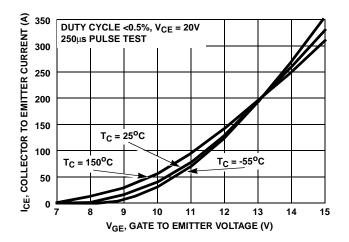


FIGURE 13. TRANSFER CHARACTERISTIC

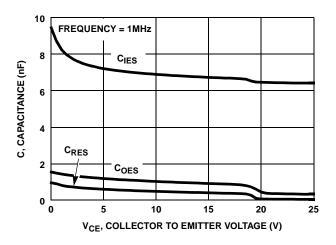


FIGURE 15. CAPACITANCE vs COLLECTOR TO EMITTER VOLTAGE

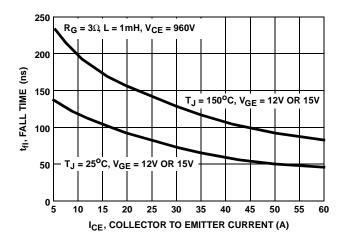


FIGURE 12. FALL TIME vs COLLECTOR TO EMITTER CURRENT

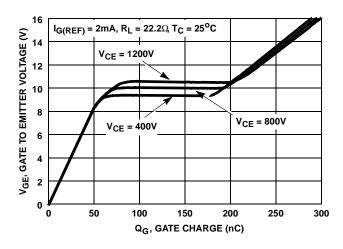
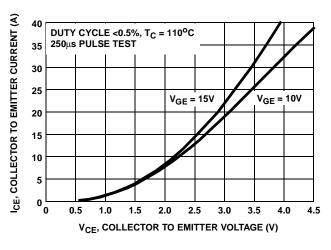


FIGURE 14. GATE CHARGE WAVEFORMS





Typical Performance Curves Unless Otherwise Specified (Continued)

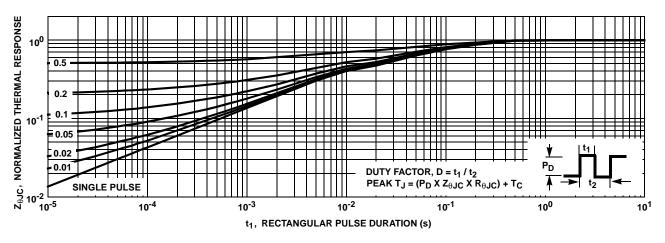


FIGURE 17. NORMALIZED TRANSIENT THERMAL RESPONSE, JUNCTION TO CASE

Test Circuit and Waveforms

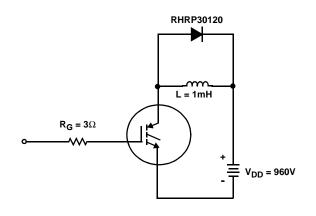


FIGURE 18. INDUCTIVE SWITCHING TEST CIRCUIT

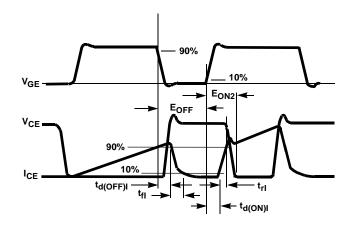


FIGURE 19. SWITCHING TEST WAVEFORMS

Handling Precautions for IGBTs

Insulated Gate Bipolar Transistors are susceptible to gate-insulation damage by the electrostatic discharge of energy through the devices. When handling these devices, care should be exercised to assure that the static charge built in the handler's body capacitance is not discharged through the device. With proper handling and application procedures, however, IGBTs are currently being extensively used in production by numerous equipment manufacturers in military, industrial and consumer applications, with virtually no damage problems due to electrostatic discharge. IGBTs can be handled safely if the following basic precautions are taken:

- Prior to assembly into a circuit, all leads should be kept shorted together either by the use of metal shorting springs or by the insertion into conductive material such as "ECCOSORBD™ LD26" or equivalent.
- 2. When devices are removed by hand from their carriers, the hand being used should be grounded by any suitable means for example, with a metallic wristband.
- 3. Tips of soldering irons should be grounded.
- 4. Devices should never be inserted into or removed from circuits with power on.
- 5. Gate Voltage Rating Never exceed the gate-voltage rating of V_{GEM} . Exceeding the rated V_{GE} can result in permanent damage to the oxide layer in the gate region.
- 6. **Gate Termination** The gates of these devices are essentially capacitors. Circuits that leave the gate open-circuited or floating should be avoided. These conditions can result in turn-on of the device due to voltage buildup on the input capacitor due to leakage currents or pickup.
- 7. **Gate Protection** These devices do not have an internal monolithic Zener diode from gate to emitter. If gate protection is required an external Zener is recommended.

Operating Frequency Information

Operating frequency information for a typical device (Figure 3) is presented as a guide for estimating device performance for a specific application. Other typical frequency vs collector current (I_{CE}) plots are possible using the information shown for a typical unit in Figures 5, 6, 7, 8, 9 and 11. The operating frequency plot (Figure 3) of a typical device shows f_{MAX1} or f_{MAX2} ; whichever is smaller at each point. The information is based on measurements of a typical device and is bounded by the maximum rated junction temperature.

 f_{MAX1} is defined by $f_{MAX1} = 0.05/(t_{d(OFF)I} + t_{d(ON)I})$. Deadtime (the denominator) has been arbitrarily held to 10% of the on-state time for a 50% duty factor. Other definitions are possible. $t_{d(OFF)I}$ and $t_{d(ON)I}$ are defined in Figure 19. Device turn-off delay can establish an additional frequency limiting condition for an application other than T_{JM} . $t_{d(OFF)I}$ is important when controlling output ripple under a lightly loaded condition.

$$\begin{split} f_{MAX2} & \text{is defined by } f_{MAX2} = (P_D - P_C)/(E_{OFF} + E_{ON2}). \text{ The} \\ \text{allowable dissipation } (P_D) \text{ is defined by } P_D = (T_{JM} - T_C)/R_{\theta JC}. \\ \text{The sum of device switching and conduction losses must} \\ \text{not exceed } P_D. \text{ A 50\% duty factor was used (Figure 3) and} \\ \text{the conduction losses } (P_C) \text{ are approximated by} \\ P_C = (V_{CE} \times I_{CE})/2. \end{split}$$

 E_{ON2} and E_{OFF} are defined in the switching waveforms shown in Figure 19. E_{ON2} is the integral of the instantaneous power loss ($I_{CE} \times V_{CE}$) during turn-on and E_{OFF} is the integral of the instantaneous power loss ($I_{CE} \times V_{CE}$) during turn-off. All tail losses are included in the calculation for E_{OFF} ; i.e., the collector current equals zero ($I_{CE} = 0$).

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EnSigna™	<i>i-Lo</i> ™	OCX™	RapidConfigure™	TruTranslation™
FACT™	ImpliedDisconnect™	OCXPro™	RapidConnect™	UHC™
FACT Quiet Serie		OPTOLOGIC [®]	µSerDes™	UltraFET [®]
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		Rev. 113